

Notice of References Cited	Application/Control No. 10/606,259	Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
	Examiner /BINH K. TIEU/	Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0018632	01-2005	Lee et al.	370/329
*	B	US-2005/0010653	01-2005	McCanne, Steve	709/219
*	C	US-2004/0152439	08-2004	Kimura et al.	455/403
*	D	US-2002/0039367	04-2002	Seppala et al.	370/401
*	E	US-7,120,131	10-2006	Seppala et al.	370/310
*	F	US-2007/0038610	02-2007	Omoigui, Nosa	707/003
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	O					
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	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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